

<b>Notice of References Cited</b>	Application/Control No. 10/778,020	Applicant(s)/Patent Under Reexamination TSUCHIYA, HITOSHI	
	Examiner (Nancy) Thanh-Nhan P. Nguyen	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0149728	10-2002	Ogishima et al.	349/129
	B	US-			
	C	US-			
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